

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/646,470	CHIEN ET AL.	
Examiner	Art Unit	
Nashaat T. Nashed, Ph. D.	1656	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
WEST Search	5/11/2007	NASH	
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